

## Cp E 432: Testing of Computing Systems

### ELECTRICAL ENGINEERING

Physical defects from semiconductor manufacture, fault modeling and simulation, fault activation and detection in digital systems, digital test pattern synthesis, test coverage, test compaction, online/offline/BIST testing concepts, design-for-test, design-for-manufacture, system testability and diagnosability.  
3 Credits

#### Prerequisites

- [EE E 351: Models and Circuits I](#) \$target.descriptions.MinimumGrade\$
- [EE E 385: Advanced Digital Systems](#) \$target.descriptions.MinimumGrade\$
- [EE E 386: Advanced Digital Systems Laboratory](#) \$target.descriptions.MinimumGrade\$

#### Instruction Type(s)

- Lecture: Lecture for Cp E 432

#### Subject Areas

- [Computer Engineering, General](#)

#### Related Areas

- [Computer Hardware Engineering](#)

